Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/633,313	KAMMA, HIROSHI
Examiner	Art Unit
DANH C. LE	2683

SEARCHED					
Class	Subclass	Date	Examiner		
+55	411	7/28/05	DX L		
	410				
	412.1				
379	102.03				
340	546				
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
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Inventor Name Search (For Double Patent Check)	7/28/05	DCL
EAST Swich USP, USPUB	7/29/05	DCL
EAST Search DERWENT, JRO, EAO	7/29/05	DCL
Interference Search		
Lee Nguyen (455)		
Hun Vuong (455)		